

Analog Test System

T7912

Tests general-purpose logic and analog devices at low costs.



Diversification of applications such as digital home appliences, mobilephones and office automation peripherals is giving rise together with detailed manufacturing processes to high-speed, highaccuracy and high-function generalpurpose logic ICs, general purpose analog Ics, optical semiconductor devices and discrete devices. The T7912 developed based on these device-measuring technologies cultivated in a lapse of long time is an analog test system that supports performance evaluation as well as mass production tests. It will strongly assist customers' businesses enabling high quqlity tests of excellent cost performance as well.

The system configuration matched for intended use

An optimal system construction can be chosen according to intendeduse, because it can be used on the same platform in its minimum and maximum construction. Moreover, a maximum of up to eight simultaneous measurements of high speed and high accuracy have been realized to contribute to improvement in the throughput during mass production.

Improvement in the speed of DC examination with the high-speed par-pin DC

It is possible to measure analog pins at high speed and with high precision which increase in accordance with the loading of parpin DC units with a maximum of 72 pins.

Device program creation tools

Since a menu-driven method is used as tools for device and program creation, device programs can be easily created.(Option Software)

T7912 Key Specifications

Target Devices:	General-purpose Logic IC, General-purpose Analog IC, Optical semiconductor device, Discrete device etc.							
Parallel Testing:	Max.8 devices							
Basic Configuration								
Device Power Supply:	2 channels to max. 8 channels							
	±128V/±32mA, ±64V/±64mA, ±16V/±500mA ±16V/±2A(pulse)							
Power Supply for I/O:	8 channels to max. 64 channels ±64V/±32mA, ±16V/±64mA							
Option High Voltage Power Su	pply: 1 channel to 8 channels(MPX switch)							

High Voltage Power Supply: 1 channel to 8 channels(MF +2kV/+1mA(per 1 channel)



On-screen examples of the T7912

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On-screen examples No.1 of device program creation tools

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On-screen examples No.2 of device program creation tools

Please refer to product manual for complete system specifications. Specifications may change without notification.



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